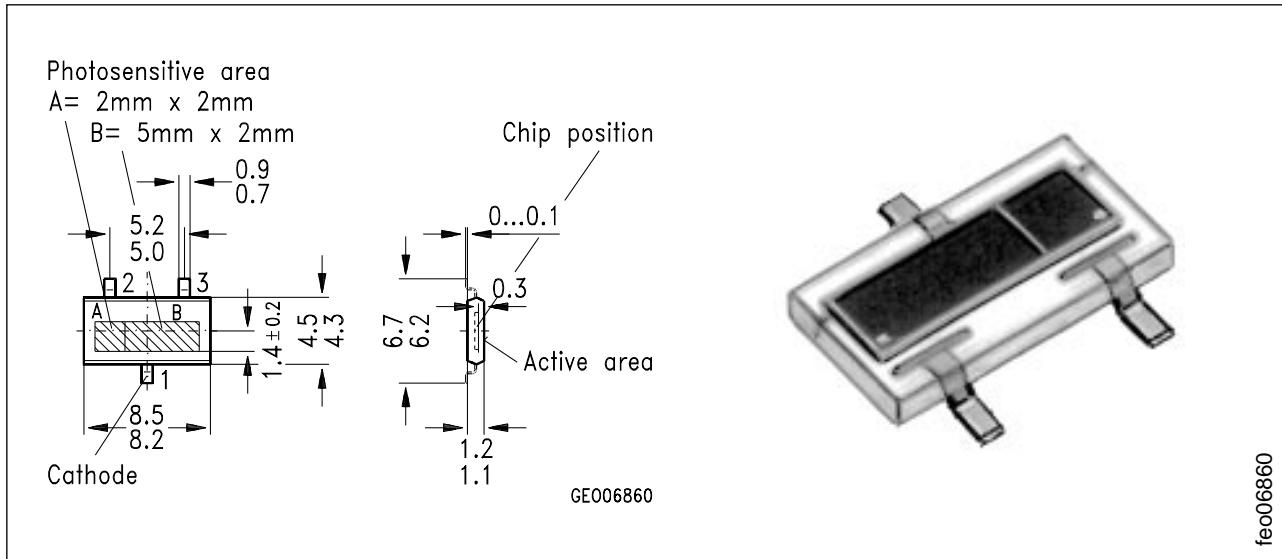


**NEU: 2fach-Silizium-PIN-Fotodiode in SMT
NEW: 2-Chip Silicon PIN Photodiode in SMT**

KOM 2125



Maße in mm, wenn nicht anders angegeben/Dimensions in mm, unless otherwise specified.

fe006860

Wesentliche Merkmale

- Speziell geeignet für Anwendungen im Bereich von 400 nm bis 1100 nm
- Kurze Schaltzeit (typ. 25 ns)
- geeignet für Vapor-Phase Löten und IR-Reflow-Löten
- SMT-fähig

Anwendungen

- Nachlaufsteuerungen
- Kantenführung
- Industrieelektronik
- "Messen/Steuern/Regeln"

Features

- Especially suitable for applications from 400 nm to 1100 nm
- Short switching time (typ. 25 ns)
- Suitable for vapor-phase and IR-reflow soldering
- Suitable for SMT

Applications

- Follow-up controls
- Edge drives
- Industrial electronics
- For control and drive circuits

Typ Type	Bestellnummer Ordering Code
KOM 2125	Q62702-K0047

Grenzwerte**Maximum Ratings**

Bezeichnung Description	Symbol Symbol	Wert Value	Einheit Unit
Betriebs- und Lagertemperatur Operating and storage temperature range	$T_{op}; T_{stg}$	-40 ... +80	°C
Sperrspannung Reverse voltage	V_R	60	V
Verlustleistung, $T_A = 25$ °C Total power dissipation	P_{tot}	150	mW

Kennwerte ($T_A = 25$ °C, Normlicht A, 2856 K)**Characteristics ($T_A = 25$ °C, standard light A, 2856 K)**

Bezeichnung Description	Symbol Symbol	Wert Value	Einheit Unit
Fotoempfindlichkeit, $V_R = 5$ V; Spectral sensitivity	Diode A Diode B	S 40 (≥ 30) 100 (≥ 75)	nA/lx
Wellenlänge der max. Fotoempfindlichkeit Wavelength of max. sensitivity	$\lambda_{S_{max}}$	850	nm
Spektraler Bereich der Fotoempfindlichkeit $S = 10\%$ von S_{max} Spectral range of sensitivity $S = 10\%$ of S_{max}	λ	400 ... 1100	nm
Bestrahlungsempfindliche Fläche Radiant sensitive area	Diode A Diode B	A 4 10	mm ²
Abmessung der bestrahlungsempfindlichen Fläche Dimensions of radiant sensitive area	$L \times B$ $L \times W$	2 × 2, 2 × 5	mm × mm
Abstand Chipoberfläche zu Vergußoberfläche Distance chip front to case seal	H	0.3	mm
Halbwinkel Half angle	ϕ	± 60	Grad deg.
Dunkelstrom, $V_R = 10$ V Dark current	Diode A Diode B	I_R 5 (≤ 30) 10 (≤ 30)	nA
Spektrale Fotoempfindlichkeit Spectral sensitivity	S_λ	0.62	A/W
Quantenausbeute Quantum yield	η	0.90	Electrons Photon

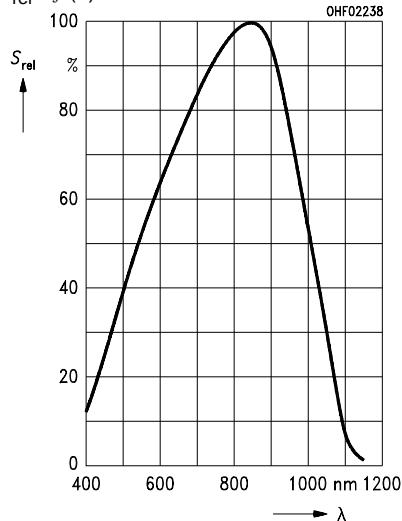
Kennwerte ($T_A = 25^\circ\text{C}$, Normlicht A, 2856 K)

Characteristics ($T_A = 25^\circ\text{C}$, standard light A, 2856 K) (cont'd)

Bezeichnung Description	Symbol Symbol	Wert Value	Einheit Unit
Leerlaufspannung, $E_v = 1000 \text{ lx}$ Open-circuit voltage	V_o	350 (≥ 300)	mV
Kurzschlußstrom, $E_v = 1000 \text{ lx}$ Short-circuit current	Diode A Diode B	I_{sc} 38 95	μA
Anstiegszeit/Abfallzeit Rise and fall time	Diode A Diode B	t_r, t_f 18 25	ns
$R_L = 50 \Omega$; $V_R = 5 \text{ V}$; $\lambda = 850 \text{ nm}$; $I_P = 800 \mu\text{A}$			
Durchlaßspannung, $I_F = 100 \text{ mA}$; $E = 0$ Forward voltage	V_F	1.0	V
Kapazität Capacitance	Diode A Diode B	C_0 40 100	pF
$V_R = 0 \text{ V}$; $f = 1 \text{ MHz}$; $E = 0$			
Temperaturkoeffizient von V_o Temperature coefficient of V_o	TC_V	-2.6	mV/K
Temperaturkoeffizient von I_P Temperature coefficient of I_P	TC_I	0.18	%/K
Rauschäquivalente Strahlungsleistung Noise equivalent power	Diode A Diode B	NEP 6.4 $\times 10^{-14}$ 9.1 $\times 10^{-14}$	$\frac{\text{W}}{\sqrt{\text{Hz}}}$
$V_R = 10 \text{ V}$			
Nachweisgrenze, $V_R = 10 \text{ V}$ Detection limit	Diode A Diode B	D^* 3.1 $\times 10^{12}$ 3.5 $\times 10^{12}$	$\frac{\text{cm} \cdot \sqrt{\text{Hz}}}{\text{W}}$

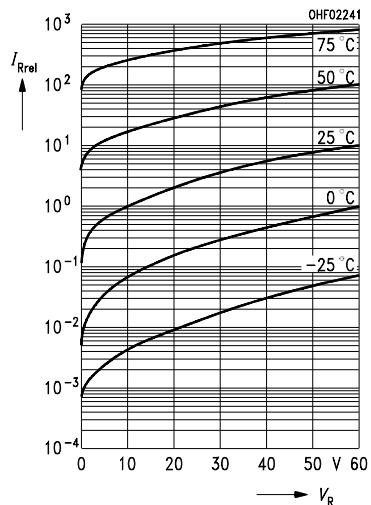
Relative spectral sensitivity

$$S_{\text{rel}} = f(\lambda)$$



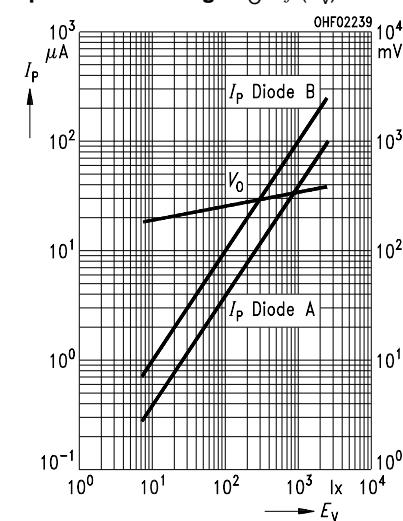
Dark current, $I_R = f(V_R)$, $E = 0$

normalized to 10 V/25 °C



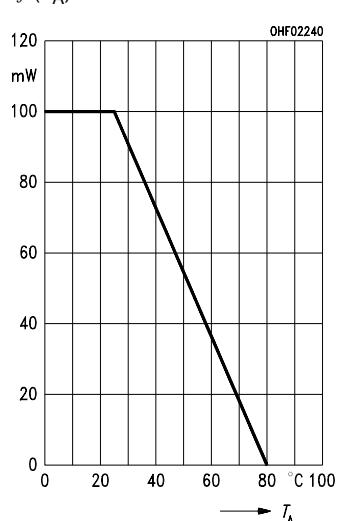
Photocurrent $I_P = f(E_V)$, $V_R = 5 \text{ V}$

$$V_O = f(E_V)$$



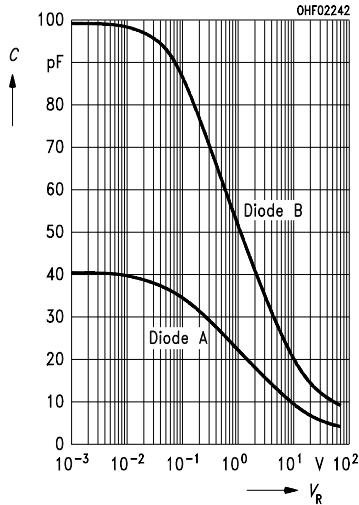
Total power dissipation

$$P_{\text{tot}} = f(T_A)$$



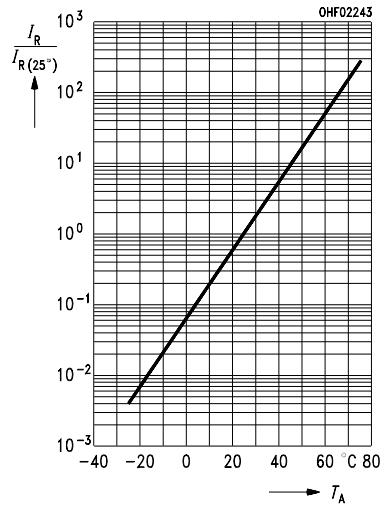
Capacitance

$$C = f(V_R), f = 1 \text{ MHz}, E = 0$$



Dark current $I_R = f(T_A)$,

$V_R = 10 \text{ V}$, $E = 0$, normalized to $T_A = 25 \text{ °C}$



Directional characteristics $S_{\text{rel}} = f(\phi)$

